INDEX FOR VOLUME 70

Articles

Presidential Address.

Cudeck, Robert. *Fitting Psychometric Models with Methods Based on Automatic Differentiation.* 599–617.

Invited Address.

Luce, R. Duncan. *Measurement Analogies: Comparisons of Behavioral and Physical Measures.* 227–251.

Theory and Methods

Bartolucci, Francesco & Forcina, Antonio. *Likelihood Inference on the Underlying Structure of IRT Models.* 31–43.

Bertolli-Barsotti, Lucio. *On the Existence and Uniqueness of JML Estimates for the Partial Credit Model.* 517–531.

Bock, Darrell R. (See Schilling, Stephen)

Brusco, Michael J. & Stahl, Stephanie. *Optimal Least-Squares Unidimensional Scaling: Improved Branch-and-Bound Procedures and Comparison to Dynamic Programming.* 253–270.

Busing, Frank M.T.A., Groenen, Patrick & Heiser, Willem. *Avoiding Degeneracy in Multidimensional Unfolding by Penalizing on the Coefficient of Variation.* 71–98.

Busing, Frank M.T.A. (See Van Deun, Katrijn)

Ceulemans, Eva & Van Mechelen, Iven. *Hierarchical Classes Models for Three-Way Three-Mode Binary Data: Interrelations and Model Selection.* 461–480.

Chan, Wai. (See Yuan, Ke-Hai)

Chang, Yuan-chin Ivan. *Application of Sequential Interval Estimation to Adaptive Mastery Testing.* 685–713.

Chen, Yuguo & Small, Dylan. *Exact Tests for the Rasch Model via Sequential Importance Sampling.* 11–30.

Colonius, Hans. (See Townsend, James)

Coupland, Jennifer Chang. (See DeSarbo, Wayne)

Damien, Paul. (See Gupta, Jayanti)

de Boeck, Paul. (See Rijmen, Frank)

de Boeck, Paul. (See Tuerlinckx, Francis)

de Rooij, Mark & Heiser, Willem. *Graphical Representations and Odds Ratios in a Distance Association Model for the Analysis of Cross-Classified Data.* 99–122.

Delbeke, L. (See van Deun, Katrijn)

DeSarbo, Wayne, Coupland, Jennifer Chang, Fong, Duncan K.H. & Liechty, John. *Evolutionary Preference/Utility Functions: A Dynamic Perspective.* 179–202.

Erosheva, Elena A. *Comparing Latent Structures of the Grade of Membership, Rasch and Latent Class Models.* 619–628.

Fong, Duncan K.H. (See DeSarbo, Wayne)

Forcina, Antonio. (See Bartolucci, Francesco)

Glas, Cees A.W. (See Jansen, Margo)

Glickman, Mark E., Gray, Jeremy R. & Morales, Carlos J. *Combining Speed and Accuracy to Assess Error-Free Cognitive Processes.* 405–426.

Glickman, Mark E., Gray, Jeremy R. & Morales, Carlos J. *Rejoinder: Combining Speed and Accuracy to Assess Error-free Cognitive Processes.* 431–432.

Gray, Jeremy R. (See Glickman, Mark E.)

Groenen, Patrick. (See Busing, Frank M.T.A.)

Groenen, Patrick. (See Van Deun, Katrijn)
Gupta, Jayanti & Damien, Paul. *Prior Distributions on Symmetric Groups*. 169–177.
Hayashi, Kentaro. (See Yuan, Ke-Hai)
Heiser, Willem. (See Busing, Frank M.T.A.)
Heiser, Willem. (See de Rooij, Mark)
Heiser, Willem. (See Van Deun, Katrijn)
Hessen, Dave. *Constant Latent Odds-Ratios Models and the Mantel-Haenszel Null Hypothesis*. 497–516.
Huang, Guan-Hua. *Selecting the Number of Classes under Latent Class Regression: A Factor Analytic Analogue*. 325–345.
Hwang, Heungsun. (See Takane, Yoshio)
Jansen, Margo & Glas, Cees A.W. *Checking the Assumptions of Rasch's Model for Speed Tests*. 671–684.
Jedidi, Kamel. (See Kohli, Rajeev)
Kiers, Henk A.L., Vicari, Donatella & Vichi, Maurizio. *Simultaneous Classification and Multidimensional Scaling with External Information*. 433–460.
Kohli, Rajeev & Jedidi, Kamel. *Probabilistic Subset-Conjunction*. 759–772.
Li, Wen. (See Zinbarg, Richard)
Liechty, John. (See DeSarbo, Wayne)
Morales, Carlos J. (See Glickman, Mark E.)
Revelle, William. (See Zinbarg, Richard)
Revuelta, Javier. *An Item Response Model For Nominal Data Based on the Rising Selection Ratios Criterion*. 305–324.
Rijmen, Frank & de Boeck, Paul. *A Relation Between the Between-Item Multidimensional IRT Model and the Mixture Rasch Model*. 481–496.
Rijmen, Frank, de Boeck, Paul & Van der Maas, Han L.J. *An IRT Model with a Parameter-Driven Process for Change*. 651–669.
Rocci, Roberto & Vichi, Maurizio. *Three-Mode Component Analysis with Crisp or Fuzzy Partition of Units*. 715–736.
Rouder, Jeff. *The Applicability of Deadline Models: Comment on Glickman, Gray, and Morales (2005)*. 427–430.
Schilling, Stephen & Bock, Darrell R. *High-Dimensional Maximum Marginal Likelihood Item Factor Analysis by Adaptive Quadrature*. 533–556.
Schuster, Christof & Smith, David A. *Dispersion Weighted Kappa: An Integrative Framework for Metric and Nominal Scale Agreement Coefficients*. 135–146.
Shieh, Gwowen. *Power and Sample Size Calculations for Multivariate Linear Models with Random Explanatory Variables*. 347–358.
Small, Dylan. (See Chen, Yuguo)
Smith, David A. (See Schuster, Christof)
Stahl, Stephanie. (See Brusco, Michael J.)
Takane, Yoshio & Hwang, Heungsun. *On a Test of Dimensionality in Redundancy Analysis*. 271–281.
Townsend, James & Colonius, Hans. *Variability of the MAX and MIN Statistic: A Theory of the Quantile Spread as a Function of Sample Size*. 759–772.
Tuerlinckx, Francis & de Boeck, Paul. *Two Interpretations of the Discrimination Parameter*. 629–650.
van der Ark, L. Andries. *Stochastic Ordering of the Latent Trait by the Sum Score Under Various Polytomous IRT Models*. 283–304.
Van der Maas, Han L.J. (See Rijmen, Frank)

Van Deun, Katrijn, Groenen, Patrick, Heiser, Willem, Busing, Frank M.T.A. & Delbeke, L. *Interpreting Degenerate Solutions in Unfolding by Use of the Vector Model and the Compensatory Distance Model*. 45–69.
Van Mechelen, Iven. (See Ceulemans, Eva)
Vicari, Donatella. (See Kiers, Henk A.L.)
Vichi, Maurizio. (See Kiers, Henk A.L.)
Vichi, Maurizio. (See Rocci, Roberto)
Yovel, Iftah. (See Zinbarg, Richard)
Yuan, Ke-Hai & Chan, Wai. *On Nonequivalence of Several Procedures of Structural Equation Modeling*. 791–798.
Yuan, Ke-Hai & Hayashi, Kentaro. *On Muthen's Maximum Likelihood for Two-level Covariance Structure Models*. 147–167.
Zinbarg, Richard, Li, Wen, Revelle, William & Yovel, Iftah. *Cronbach's a, Revelle's β, McDonald's ω_H: Their Relations with Each and Two Alternative Conceptualizations of Reliability*. 123–133.

Application Reviews and Case Studies
Bowles, Ryan P. (See Ram, Nilan)
Chow, Sy Miin. (See Ram, Nilan)
Fijita, Frank. (See Ram, Nilan)
Grimm, Kevin. (See Ram, Nilan)
Haviland, Amelia M. & Nagin, Daniel. *Causal Inferences with Group Based Trajectory Models*. 557–578.
Nagin, Daniel. (See Haviland, Amelia M.)
Nesselroade, Frank R. (See Ram, Nilan)
Ram, Nilan, Chow, Sy Miin, Bowles, Ryan P., Wang, Lijuan, Grimm, Kevin, Fujita, Frank & Nesselroade, Frank R. *Examining Interindividual Differences in Cyclicity of Pleasant and Unpleasant Affect Using Spectral Analysis and Item Response Modeling*. 773–790.
Rouder, Jeff. *Are Unshifted Distributional Models Appropriate for Response Time*. 377–381.
Van Breukelen, Gerard J. P. *Psychometric Modeling of Response Speed and Accuracy with Mixed and Conditional Regression*. 359–376.
Van Breukelen, Gerard J. P. *Psychometrics, Psychonomics, Psychonometrics: Rejoinder To Rouder And Wenger*. 389–391.
Wang, Lijuan. (See Ram, Nilan)
Wenger, Michael J. *Models for the Statistics and Mechanisms of Response Speed and Accuracy*. 383–388.

Notes and Comments.
Bryant, Damon U. *A Note on Item Information in Any Direction for the Multidimensional Three-Parameter Logistic Model*. 213–216.
Hayashi, Kentaro & Kamata, Akihito. *A Note on the Estimator of the Alpha Coefficent for Standardized Variables Under Normality*. 579–586.
Kamata, Akihito. (See Hayashi, Kentaro)
Mueller, Shane T. (See Zhang, Jun)
Yuan, Ke-Hai, & Chan, Wai *On Nonequivalence of Several Procedures of Structural Equation Modeling*. 791–798.
Zhang, Jun & Mueller, Shane T. *A Note on ROC Analysis and Non-Parametric Estimate of Sensitivity*. 203–212.

Reviews
ten Berge, Jos. *J.C. GOWER & G.B. DIJKSTERHUIS. Procrustes Problems*. 791–798.